

# **Notice of References Cited**

Application/Control No.

10/699,500

Applicant(s)/Patent Under  
Reexamination  
CHEN, PHILIP CHUNG-HWEI

Examiner

Stykin Ip

Art Unit

1742

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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